TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ( $L^2$ - $\pi$ -MOSV)

## 2SK2782

# Chopper Regulator, DC/DC Converter and Motor Drive Applications

• 4 V gate drive

• Low drain-source ON-resistance  $: RDS (ON) = 0.039 \Omega (typ.)$ 

 $\bullet~$  High forward transfer admittance ~ : |  $Y_{fs}\,|$  = 11 S (typ.)

• Low leakage current  $: I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 60 \text{ V)}$ 

• Enhancement mode :  $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$ 

#### **Absolute Maximum Ratings (Ta = 25°C)**

Character	istic	Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	60	V
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		$V_{DGR}$	60	٧
Gate-source voltage		$V_{GSS}$	±20	٧
Drain current	DC (Note 1)	ΙD	20	Α
	Pulse (Note 1)	$I_{DP}$	50	Α
Drain power dissipatio	n (Tc = 25°C)	$P_{D}$	40	W
Single-pulse avalanche energy (Note 2)		Eas	156	mJ
Avalanche current		I <sub>AR</sub>	20	Α
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	4	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

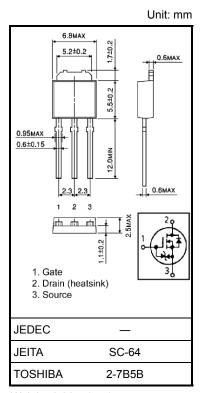
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.125	°C / W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	125	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

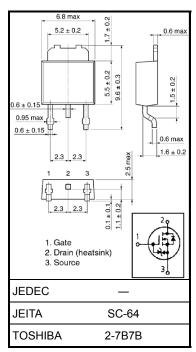
Note 2:  $V_{DD}$  = 25 V,  $T_{ch}$  = 25°C (initial), L = 530  $\mu$ H,  $R_{G}$  = 25  $\Omega$ ,  $I_{D}$  = 20 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



Weight: 0.36 g (typ.)



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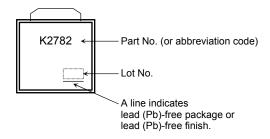
### **Electrical Characteristics (Ta = 25°C)**

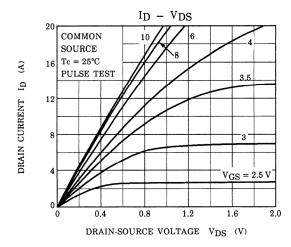
Chara	cteristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ	
Drain cutoff curr	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V	_	_	100	μΑ	
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_	_	V	
Gate threshold	voltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	8.0	_	2.0	V	
Drain-source ON-resistance		D	V <sub>DS</sub> = 4 V, I <sub>D</sub> = 5 A	_	0.06	0.09	Ω	
Diain-source O	in-resistance	R <sub>DS</sub> (ON)	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10 A	_	0.039	0.055	12	
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10 A	7	11	_	S	
Input capacitano	ce	C <sub>iss</sub>		_	880	_		
Reverse transfer capacitance Output capacitance		C <sub>rss</sub>		_	90	_	pF	
		Coss		_	330	_		
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{OV}$ $V_{OV}$ $V_{DD}$ $V_{DD}$ $V_{DD}$	_	15	_	ns	
	Turn-on time	t <sub>on</sub>		_	25	_		
	Fall time	t <sub>f</sub>		_	30	_		
	Turn-off time	t <sub>off</sub>		_	100	_		
Total gate charg		Qg			25	_		
Gate-source charge		Qgs	$V_{DD} \approx 48 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		19	_	nC	
Gate-drain ("Miller") charge		Q <sub>gd</sub>	]	_	6	_		

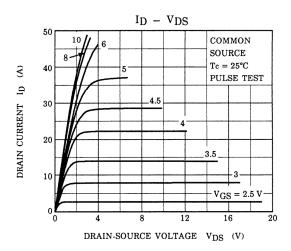
## Source-Drain Ratings and Characteristics (Ta = 25°C)

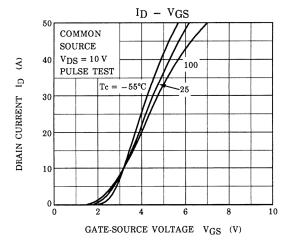
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	20	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	50	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 20 A, V <sub>GS</sub> = 0 V	_	_	-2.0	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 20 A, V <sub>GS</sub> = 0 V, dI <sub>DR</sub> / dt = 50 A / μs	_	60	_	ns
Reverse recovery charge	Q <sub>rr</sub>		_	45	_	μC

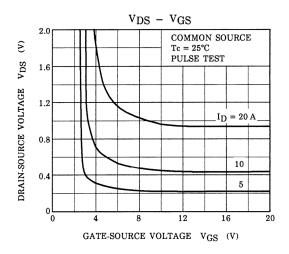
## Marking

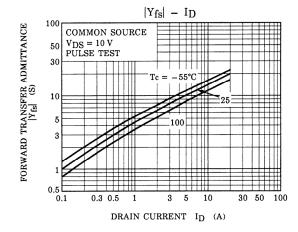


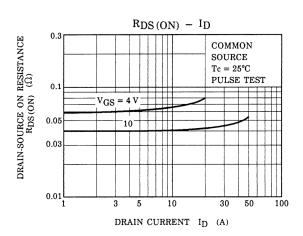




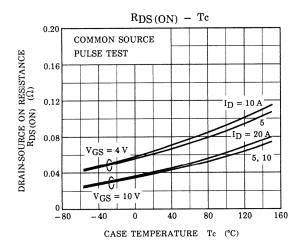


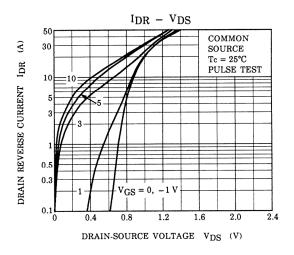


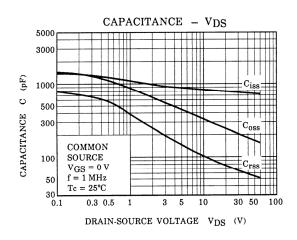


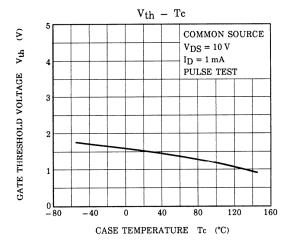


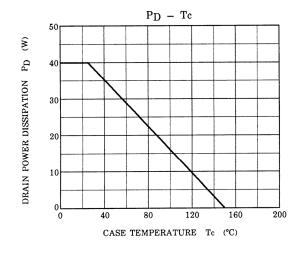
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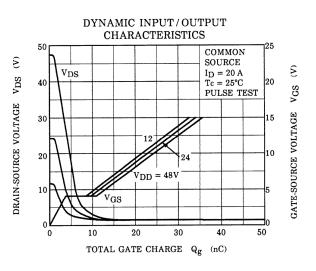








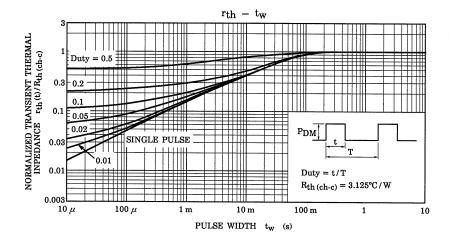


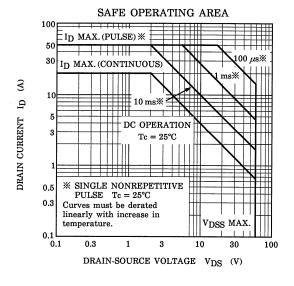


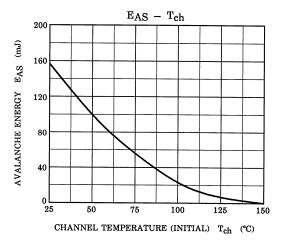
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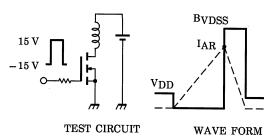
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 $v_{DS}$ 









$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 25~V,~L = 530~\mu H \end{aligned} \qquad E_{AS} &= \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{Bv_{DSS}}{Bv_{DSS} - V_{DD}} \right) \end{aligned}$$

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